



FOR IMMEDIATE RELEASE

HORIBA Semiconductor Introduces the HD-960L Monitor for the detection of PPB levels of Dissolved Oxygen

SUNNYVALE, CA June 28th, 2017 – HORIBA Semiconductor, global leader in Process Metrology and Control Components, introduces the HD-960L for parts-per-billion level monitoring of Dissolved Oxygen (DO) in chemicals, with a low sample-consumption rate. The HD-960L is specifically designed to enable processes that require ultra-low or controlled levels of DO.

The HD-960L uses an innovative polarographic sensor and an auto-ranging feature to give users real-time trace DO data from ppb level to saturation in critical process chemistries. The technology allows users to monitor DO levels, avoid process excursions due to oxidation and more effectively control silicon etch rates.

“The HD-960L’s low detection limit, high accuracy, low sample consumption and wide range make it the perfect choice for critical next-generation processes that require low levels of DO”, said Mark Mahoney, Business Development Manager for Wet Products at HORIBA Semiconductor.

HORIBA technologies for wet process monitoring and control are used globally in critical Semiconductor manufacturing processes and the HD-960L represents the latest in applications-driven, wet process monitoring technology development that supports the Semiconductor Industry.

HORIBA Semiconductor, part of HORIBA INSTRUMENTS, INC., headquartered in the United States, provides an extensive array of instruments and solutions for applications across a broad range of Semiconductor processes. HORIBA Semiconductor is a world leader in the measurement and control of critical process chemistries. Our instruments are found in equipment and facilities worldwide and HORIBA is a recognized technology leader in the Semiconductor industry.

Media Contact:

Paul Totten
Segment Marcoms Leader
HORIBA Semiconductor
paul.totten@horiba.com
(480) 221 2532